



## **Distributed Optimization for Infeasible Combined T&D Networks**

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# Combined T&D Interactions are Growing

• Future Grid will rely on approaches that enable joint operation and control of T&D resources

Source: VELCO



# Combined T&D Interactions are Growing

• Consider a sunny Spring day in VT



Source: VELCO



# DER Majority Generation is a New Reality

- VT's net load was only 100 MW on May' 23
	- $\sim$  80% of net generation from DERs in distribution nets





#### DER Growth in New-England is Accelerating



31630 MW is the expected summer demand for ISO-

**Figure:** Projected growth in PV within ISO-NE is accelerating.

Source: ISO-new England



# Example: Improved Modeling DER is Critical



Event: Transmission line trip in NY resulted in a disturbance

Source: VELCO



# Example: Improved Modeling DER is Critical



Event: Transmission line trip in NY resulted in a disturbance Consequence:  $100$  MW of DERs ( $\sim$ 15% of net VT load) tripped

Source: VELCO



# Need: Combined T&D Steady-state Analysis

- To evaluate impact of high-penetration of DERs
	- Emergency operation similar to NY line trip event
	- Normal operation asset health when continuous backflow from distribution grids is present
- Initialization of combined T&D dynamic analysis



# Need: Combined T&D Steady-state Analysis

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Aggregating the resources may not work due to heterogenous type or control of various DER devices



## SoA - Steady-state Combined T&D Analysis

- Co-simulation
	- Disparate models for T&D networks
	- Pros: Can mix-n-match various established tools
	- Cons: Lack of convergence, and robustness





## SoA - Steady-state Combined T&D Analysis

- Co-simulation
- Co-modeling
	- Unified models and algorithms for joint T&D networks



#### *and many more!*



#### SoA - Steady-state Combined T&D Analysis



#### *and many more!*

None of these approaches work when the combined T&D network has no solution



# Solving Infeasible Combined T&D Nets

- System planners require clear indications regarding why power flow simulations fail
	- Where are the system weaknesses
	- Where to consider adding new assets



# Solving Infeasible Combined T&D Nets

• System planners require clear indications regarding why power flow simulations fail

#### **Preliminaries**

- For the positive sequence transmission net; concept of missing power<sup>a</sup>, introducing slack current<sup>b</sup> using circuit simulation
- For the three-phase distribution network; identifying the weak spots<sup>c</sup>, identifying the problematic power flow constraints

<sup>a</sup>T. J. Overbye  $[2]$ <sup>b</sup>M.Jereminov, Pandey, *et al.* [3] <sup>c</sup>E.foster, Pandey, *et al.* [4]



**Goal:** Model and simulate infeasible large-scale combined positive-sequence T and three-phase D networks within the same solution and modeling framework

**Infeasible:** A combined T&D network that cannot satisfy power flow network constraints while satisfying device bounds



# Model: Equivalent Circuit (Ckt) Formulation

- Insight: Model and analyze combined T&D network as an equivalent circuit<sup>2</sup>
	- KCL: linear network constraints, nonlinear injection models





<sup>2</sup>A. Pandey *et al.* [5]

# Combined T&D Modeling - A Ckt Approach



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# Combined T&D Modeling - Coupling Ckt

• Coupling circuits<sup>3</sup> model the interactions between  $T$ and D sub-circuits using symmetrical components



**Figure:** Coupled T&D layout (coupling circuit).

<sup>3</sup>A. Pandey *et al.* [6]

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# Combined T&D Modeling – Coupling Ckt

• Real circuit coupling equations (primal setup)



*t:* is the normalizing constant  $\alpha$ : is the  $2\pi/3$ 

# Combined T&D Solution: A Ckt Approach

• Solving this circuit requires solving the KCL equation at each node and maintaining voltage mag at some





# A Circuits Approach: Adding Infeas Sources



**Figure:** Illustration of Combined T&D Ckt with Infeasibility Sources

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# A Circuits Approach: Adding Infeas Sources



**Figure:** Illustration of Combined T&D Ckt with Infeasibility Sources



# Optimization to Solve Infeasible Networks

- The objective is to minimize the norm of infeasibility currents
	- Feasible network: the objective will be 0; recover the power flow solution from primal variables
	- Infeasible network: the non-zero dual variables localizes the system weaknesses

#### Choice of norm localizes system weakness differently!



$$
\begin{aligned} &\min_{X,\mathcal{I}} \sum_{s \in S^T} \lVert (\mathcal{I}_s^T) \rVert_p + \sum_{s \in S^D} \sum_{\Omega \in a,b,c} \lVert (\mathcal{I}_{s,\Omega}^D) \rVert_p \stackrel{\text{(Minimize infeasibility}}{\text{source)}} \\ &s.t. \\ &\mathcal{F}^T_{s_t}(X^T_{s_t}) - \mathcal{I}^T_{s_t} = 0 \quad \forall s_t \in S^T \text{ (T\&D power flows)} \\ &\mathcal{F}^D_{s_d,\Omega}(X^D_{s_d,\Omega}) - \mathcal{I}^D_{s_d,\Omega} = 0 \quad \forall \Omega \in \{a,b,c\} \quad \forall s_d \in S^D \\ &\mathcal{G}^T_{s_t}(X^T_{s_t}) \leq 0 \quad \forall s_t \in S^T \text{ (T\&D voltage bounds)} \\ &\mathcal{G}^D_{s_d,\Omega}(X^D_{s_d,\Omega}) \leq 0 \quad \forall \Omega \in \{a,b,c\} \quad \forall s_d \in S^D \\ &\mathcal{C}_k(X^T,X^D) = 0 \quad \forall k \in K \text{ (Coupling constraint)} \end{aligned}
$$



# Methodology - Optimization problem

• The choice of infeasible sources:

$$
\mathcal{I} = \begin{cases} I^{R,\inf} + jI^{I,\inf} & \text{if } \mathcal{I} = I^\inf \\ (P^{\inf} - jQ^{\inf}) / (V^R - jV^I) & \text{if } \mathcal{I} = S^{\inf} \\ (G^{\inf} + jB^{\inf}) (V^R + jV^I) & \text{if } \mathcal{I} = Z^{\inf} \end{cases}
$$

- Current infeasibility  $(I)$  introduces only linear term
- Power infeasibility  $(S)$  can localize the lack of reactive power implicitly



# Methodology – Distributed optimization

#### • Centralized problem

- Unable to solve tens of millions of variables under single machine single compute framework
- Distributed problem
	- Preserve privacy between separate T&D utilities
	- Inherent weak coupling between T&D allows natural decomposition



# Methodology - Distributed optimization

- Centralized problem
- Distributed problem

In this work, we employ a distributed primal-dual interior point method (PDIP), which follows the framework of the Gauss-Jacobi Newton algorithm



#### **BBD Matrix**  $\rightarrow$  **Distributed Framework**



**Figure:** Coupled T&D layout bordered block diagonal (BBD) structure



#### BBD Matrix - Int. and Ext. Variables



**Figure:** Coupled T&D layout bordered block diagonal (BBD) structure



#### Methodology - Distributed PDIP





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# Methodology - Decomposed KKT equations



Gauss step: Dual expr. for coupling eqns. (also primal)

$$
\begin{bmatrix} \lambda_{k,a}^{R,D} \\ \lambda_{k,a}^{I,D} \\ \lambda_{k,b}^{R,D} \\ \lambda_{k,b}^{I,D} \\ \lambda_{k,c}^{R,D} \\ \lambda_{k,c}^{I,D} \\ \lambda_{k,c}^{I,D} \end{bmatrix} = \frac{1}{\kappa} \begin{bmatrix} 1 & 0 \\ 0 & 1 \\ \alpha^2 & 0 \\ 0 & \alpha^2 \\ 0 & 0 \\ 0 & \alpha \end{bmatrix} \begin{bmatrix} \lambda_k^{R,T} \\ \lambda_k^{I,T} \\ \lambda_k^{I,T} \\ \lambda_{k,c}^{I,D} \\ \end{bmatrix}
$$

 $\kappa$  is the normalizing constant;  $\alpha$ : is the  $2\pi/3$ .



## Results - Experimental Setup

- Use case: Reactive power compensation
	- Corrective action to improve voltages on transmission net due to increased loading on the distribution nets



**Table:** Test cases description

D-net: Synthetic urban meshed network with 1420 three-phase nodes (4260 single-phase nodes)





ADMM runs terminated after 1800 sec.



# Solving Real Combined T&D Network

- Combined T&D net with real VT dist. feeder
- Higher electrification → network infeasibility
	- Goal: Localize weak spots







**Figure:** VT Distribution Feeder



# Solving Real Combined T&D Network



With L2 norm, the infeasibility is distributed throughout the system



# Solving Real Combined T&D Network



With L2 norm, the infeasibility is distributed throughout the system

With L1 norm, the infeasibility is localized to few locations



# **Concluding Remarks**

- Interactions between T&D nets are growing and grid operators and planners are looking for new tools:
	- Robust: Methods converge with some guarantee
	- $-$  Scalable: Can solve real setups with  $>10e6$  variables
	- Generalized: Apply to a variety of problems



#### Come Visit Us!





#### Combined T&D - References

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[4] E. Foster, A. Pandey, and L. Pileggi, "Three-phase infeasibility analysis for distribution grid studies," *Electric Power Systems Research*, vol. 212, p. 108486, 2022.

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